

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner			Art Unit	2826	Page 1 of 1
A. Sefer					

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*	C	US-6,414,297	07-2002	Sasaki et al.	250/214R
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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